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• FAX or send the abstract, pertinent claims (not all of the claims), drawings, or chemical structures to your EIC or branch library.

I am looking for a system that tracks and analyzes the efficiency/proficiency/performance of a repair process (e.g., vehicle repairs, etc.). The system identifies causes/reasons/sources of delay in the repair process (e.g., a delay in the arrival of inventory, technician error, etc.). A code/index/identifier is associated with each cause/reason/source of delay. These codes are then categorized to identify chronic problems associated with the repair process. If you cannot find the codes per se, any sort of analysis that identifies and groups together or categorizes the most common reasons for delays in the repair process, regardless of whether or not there is an associated code, would be helpful too.

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